



Retraction Note: Capacitance pin defect detection based on deep learning

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<https://doi.org/10.1007/s10878-022-00904-8>.

The Publisher has retracted this article in agreement with the Editor-in-Chief. The article was submitted to be part of a guest-edited issue. An investigation by the publisher found a number of articles, including this one, with a number of concerns, including but not limited to compromised editorial handling and peer review process, inappropriate or irrelevant references or not being in scope of the journal or guest-edited issue. Based on the investigation's findings the publisher, in consultation with the Editor-in-Chief therefore no longer has confidence in the results and conclusions of this article.

Authors Tao Tang and Cheng Cheng have not responded to correspondence regarding this retraction. The Publisher has not been able to obtain a current email address for author Longlong Liu, Yahong Zhuang, Jie Huang and Ning Dai.

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